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# BLACK-BOX MODELLING

Response surface modelling

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# Outline

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- ▶ What's in Black-box Modelling
- ▶ Some Regression Engines
  - ▶ Artificial Neural Networks
  - ▶ Support-Vector Machines
- ▶ Importance of Data Post-processing
- ▶ Feature Selection Algorithm
- ▶ Band-gap Test-case
- ▶ Verilog-A Model (CMOS inverter)
- ▶ CMOS inverter: Model does not work !
- ▶ Algorithmic Solution to the Problem
- ▶ Conclusions (modelling tips)

# What's in Black-box Modelling

Design of Stimuli

Simulations

Feature Identification

Data Pre-processing

State-space Embedding

Regression

Implementation

Testing

- ▶ Sampling of the input-output behaviour
  - ▶ Cover all time-constants / frequencies
  - ▶ Cover all relevant amplitudes
  - ▶ Cover all meaning input combinations
- ▶ Select the training / testing data-sets
- ▶ Generate an extensive set of possible input variables (loop to reduce)
- ▶ Select the regression engine
- ▶ Select the engine's parameters
- ▶ Run the regression (model extraction)
- ▶ Validate the model



# Some Regression Engines

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## Artificial Neural Networks

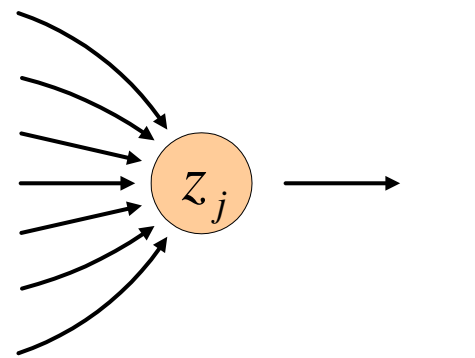
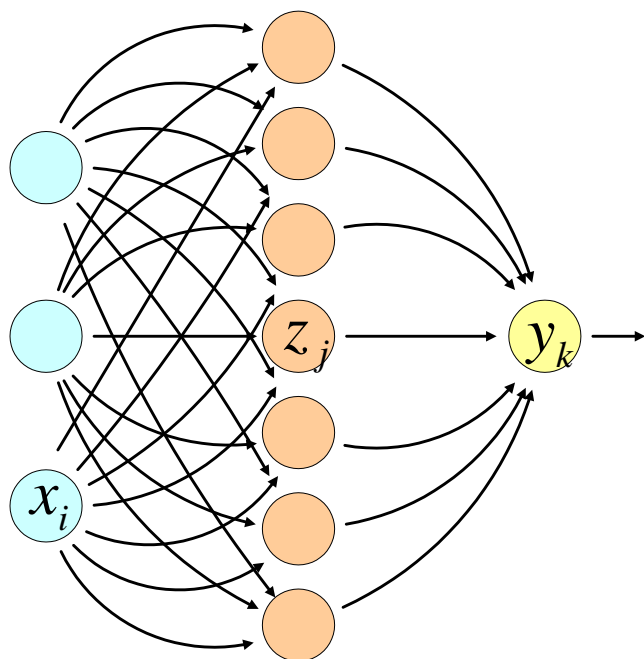
- ▶ Historically one of the first tools of machine learning
- ▶ Many publications of ANN-based models in electronics
- ▶ Known issues :
  - ▶ Sensitivity to initial condition
  - ▶ Difficult to estimate optimal parameters (eg. # layers)
  - ▶ Prone to over-fitting
  - ▶ Stability issues when feedback

## Support-Vector Machines

- ▶ Developed to overcome limitations of ANN's
- ▶ Currently behind many hand-writing recognition and data-base mining algorithms

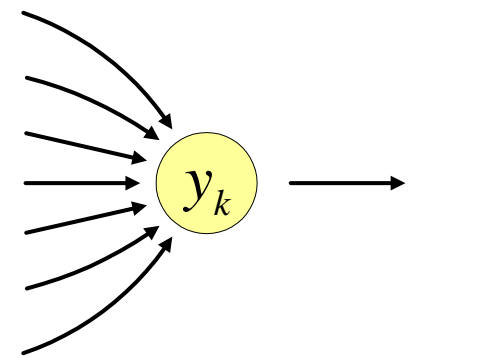
# Artificial Neural Networks

- ▶ Weighted sum of inputs
- ▶ Every neuron applies a “non-linear” threshold function
- ▶ Learning based on concept of back-propagation of errors
- ▶ **Multi-layer PERCEPTRON :**



$$a_j = \theta_j + \sum_i w_{ji} \cdot x_i$$

$$z_j = \frac{1}{1 + \exp(-a_j)}$$



$$y_k = \theta_k + \sum_j w_{kj} \cdot z_j$$

# Support-Vector Machines

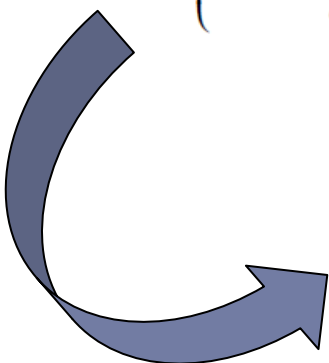
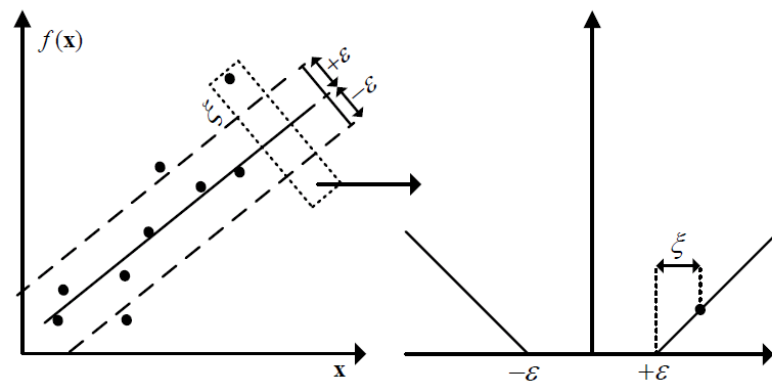
▶ SVM's realize a kind of "lean regression"

- ▶ Insensitivity tube of width  $\varepsilon$
- ▶ Model tends to minimize  $\xi$
- ▶ Model favors lower weights

$$f(\mathbf{x}) = \langle \mathbf{w}, \mathbf{x} \rangle + b,$$

minimise  $\frac{1}{2} \|\mathbf{w}\|^2 + C \sum_{i=1}^l (\xi_i + \xi_i^*)$

subject to  $\begin{cases} y_i - \langle \mathbf{w}, \mathbf{x}_i \rangle - b \leq \varepsilon + \xi \\ \langle \mathbf{w}, \mathbf{x}_i \rangle + b - y_i \leq \varepsilon + \xi_i^* \\ \xi_i, \xi_i^* \geq 0 \end{cases}$



$$y(x) = \sum_{k=1}^N \alpha_k K(x_k, x) + b \text{ with unknowns } \alpha \text{ and } b.$$

$$(w = \sum_{k=1}^N \alpha_k \varphi(x_k))$$

*Kernel function enabling high-dimensional nonlinearities*



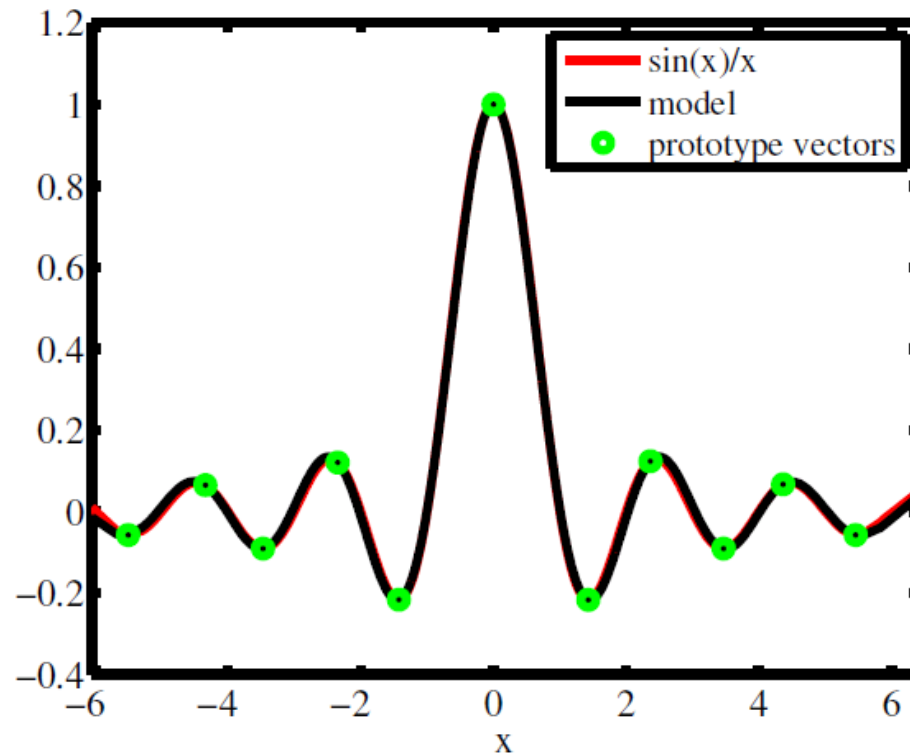
# Support-Vector Machines

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- ▶ **Very popular in machine learning :**
  - ▶ Excellent performance in a variety of learning problems;
  - ▶ Theoretical guarantees about their performance;
  - ▶ Lower susceptibility to local minima;
  - ▶ Deals well with highly dimensional input data.
- ▶ **However, machine-learning practitioners seem to have an unlimited budget for computational power**
  - ▶ Usually extraction is run targeting minimal error
  - ▶ A large model results (many SV's) which is slow to evaluate
  - ▶ Some reduction algorithms were proposed to discard SV's
- ▶ **Efficient analogue abstractions still require better...**

# Support-Vector Machine

- ▶ Constructive « active learning » :  
Only add support-vectors where absolutely necessary  
(allows to generate compact models with good accuracy)







# Importance of Data Post-processing

Pre-processing technique	Test data set NRMSE improvement
Scaling (from [-1 to 1])	34.5%
White noise	3.5%
Moving average filters (instead of time delays)	7.1%

- ▶ **Scaling / normalizing the data helps both for ANN & SVM's**
  - ▶ Otherwise there is a risk that significant errors between low-amplitude data-points are just neglected
- ▶ **Addition of white noise :**
  - ▶ improves robustness, stability and generalisation ability (Jaeger '02)
  - ▶ Avoids the risk that the extraction « focusses » on one input
  - ▶ In case of feedback loop, renders the model robust against numerical issues



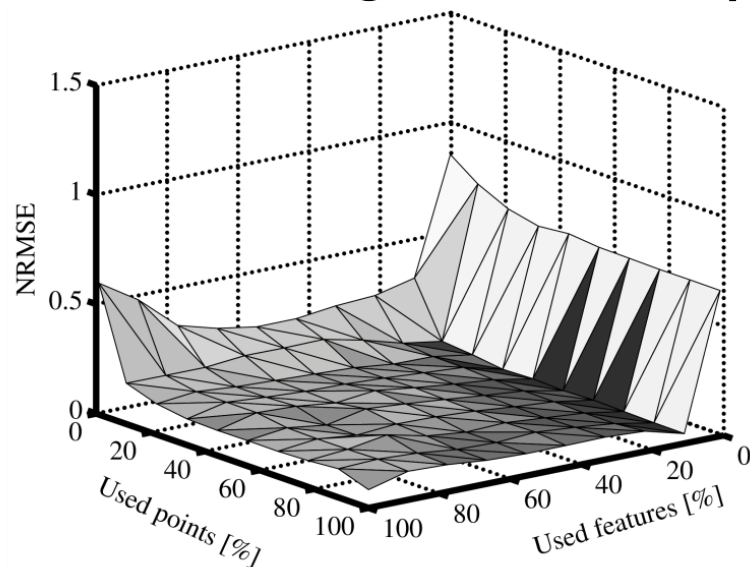
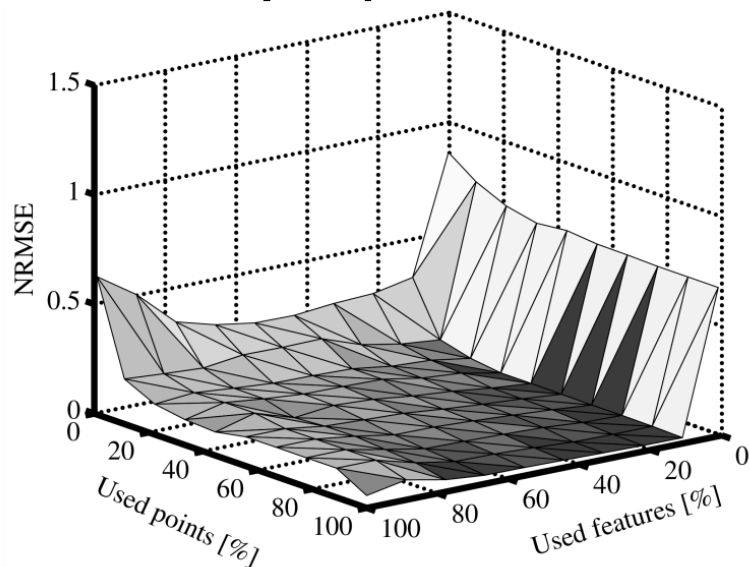
# Normalised root mean square error

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- ▶ **NRMSE =  $\sqrt{\text{mean}((t-y)^2)/\text{var}(t)}$ ;**
  - ▶ *sqrt* = square root, *mean* = mean value, *var* = variance
  - ▶ *t* = target
  - ▶ *y* = model prediction
  - ▶ 0 - perfect match

# Feature Selection Algorithm

- ▶ How many inputs do we need to achieve good accuracy ?



(a) SVM model error on the validation data (b) SVM model error on the testing data set

- ▶ **A sufficient number, but also not too many !**
- ▶ **Good correlation between training and validation data-sets**
  - ▶ Select features based on other data-set than training set usually improves the model quality



# Feature Selection Algorithm

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- ▶ Feature selection also known as subset selection or variable selection (Guyon, 2006)
  - ▶ Wrapper methods
  - ▶ Feature filtering
  - ▶ Embedded techniques
- ▶ Training point selection methods are also actively investigated, e.g.
  - ▶ (Wang, 2005) presents training data selection for support vector machines
  - ▶ (Patan, 2010) presents selection of training data for locally recurrent ANNs
  - ▶ Active learning methods can also be used for training point selection
- ▶ Zhang et al. in the recent paper (Zhang, 2012) advocate to do the feature selection and training point selection in the same time.
  - ▶ Feature and Training point Selection and Ranking = FTSR

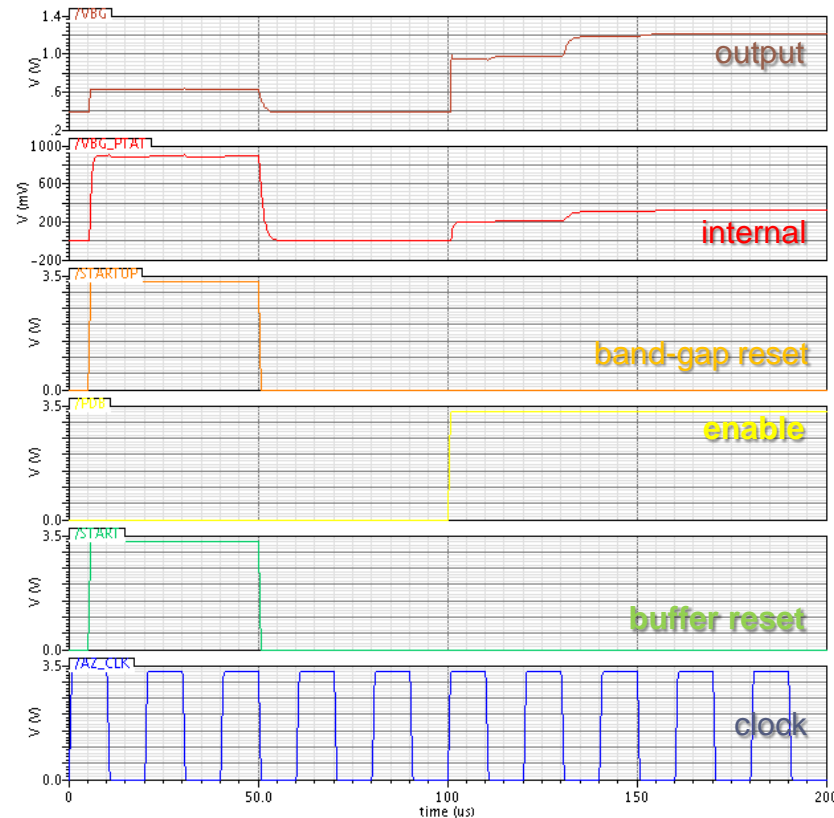
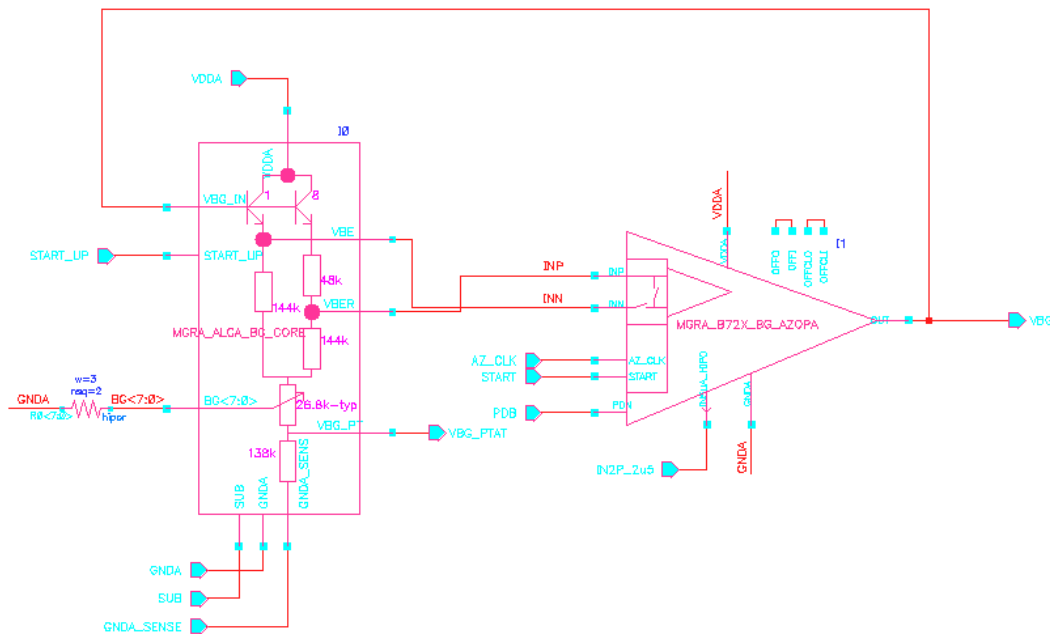
# Feature Selection Algorithm

- ▶ You can't beat a feature selection algorithm...

	FTSR	“Expert” (manual selection)	GA	PSO
NRMSE:	0.045	0.18	0.11	0.15

- ▶ FTSR : feature selection
  - ▶ GA : genetic algorithm
  - ▶ PSO : particle swarm optimization
- 
- ▶ Use feature and data-point selection methods !
  - ▶ FTSR is key to fully automate the model generation

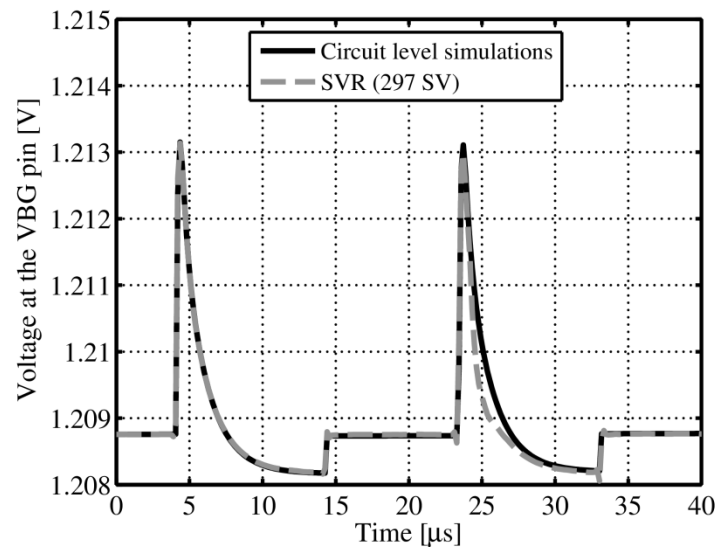
# Auto-zero Bandgap Test-case



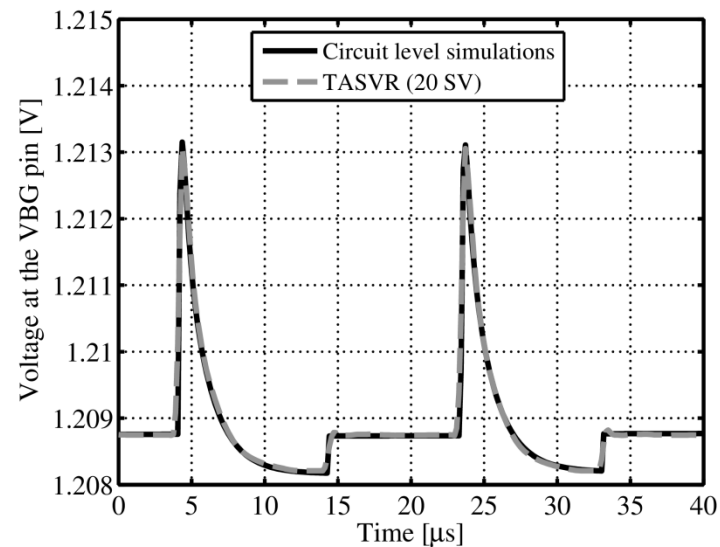
- ▶ Stable voltage reference circuit
- ▶ Followed by a buffer (to isolate from the load)
- ▶ Technology imperfections in the buffer spoil the reference
- ▶ Circuit has an auto-calibration routine (internal states)

# Band-gap Test-case

- ▶ Voltage bandgap reference with offset compensation
  - ▶ ONSEMI test-case with 242 transistors
  - ▶ modelling of the VBG voltage in the time-domain
- ▶ Comparison of standard SVR and new TASVR



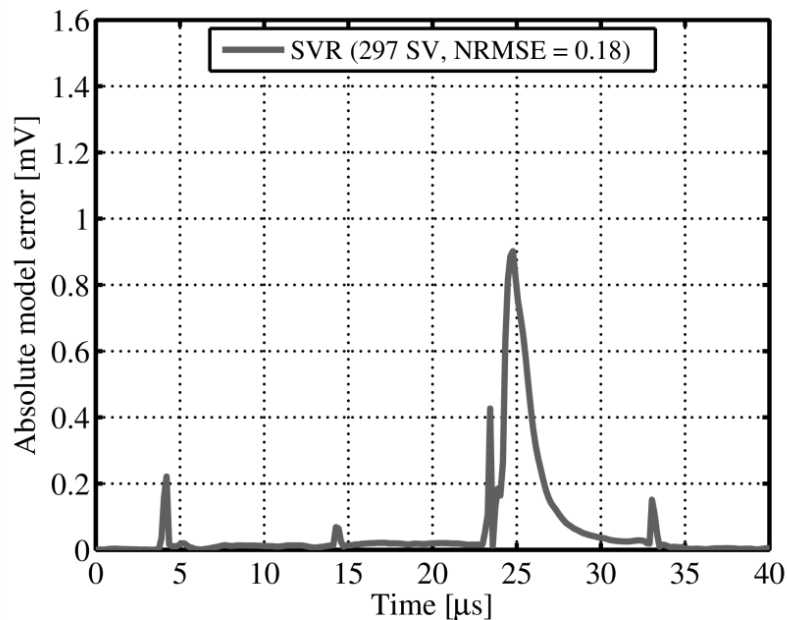
(a) SVR (**297 SVs**) vs. circuit level simulations



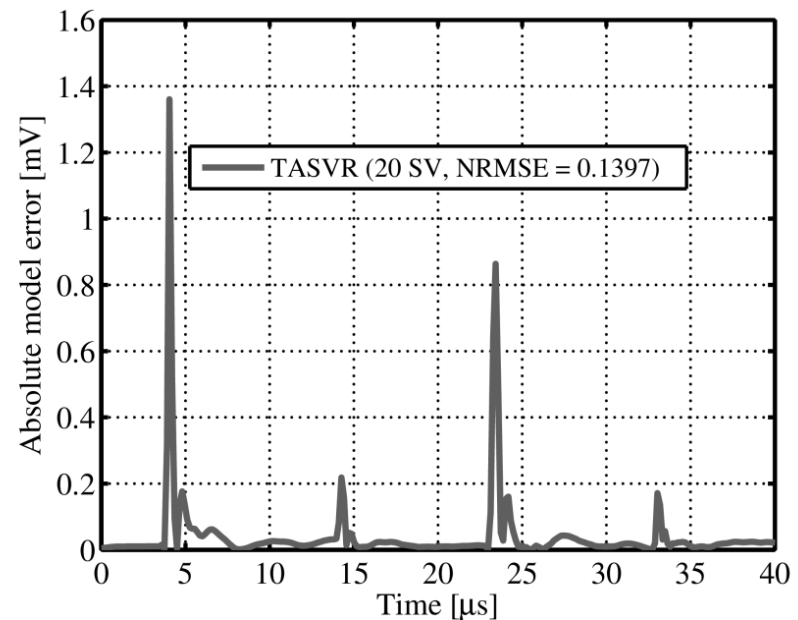
(b) TASVR (**20 SVs**) vs. circuit level simulations

# Band-gap Test-case (continued)

- ▶ Comparison of standard SVR and new TASVR :  
Absolute model Errors



(a) SVR (**297 SVs**) vs. circuit level simulations



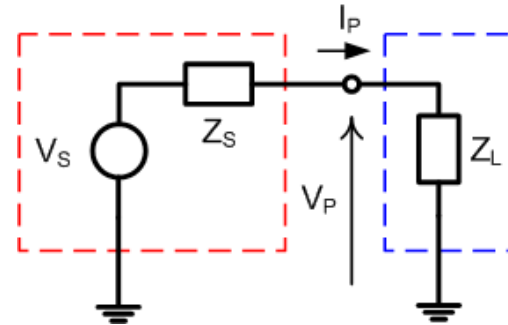
(b) TASVR (**20 SVs**) vs. circuit level simulations

- ▶ Same level of errors but TASVR >10x faster

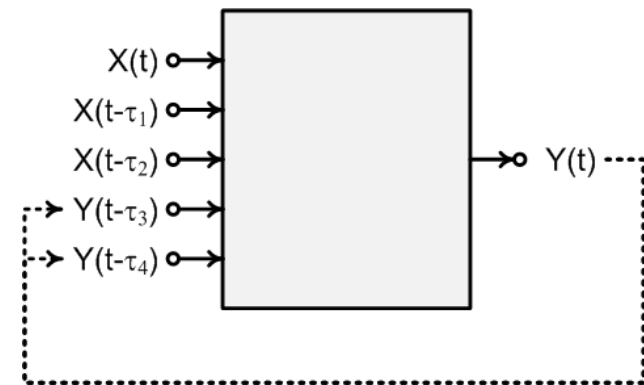


# The Problem of Ubiquitous Feedback

- ▶ Analogue circuits  $\equiv$  feedback  
(*everywhere you don't want it*)



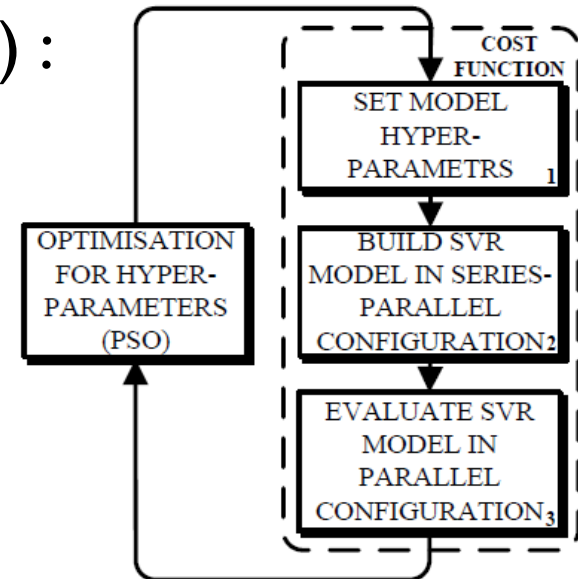
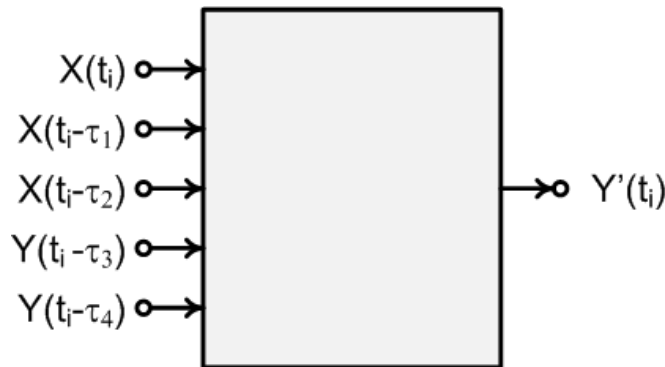
- ▶ Must generate behavioural models with multiple feedbacks :  
*eg. delayed replica's of output voltage*



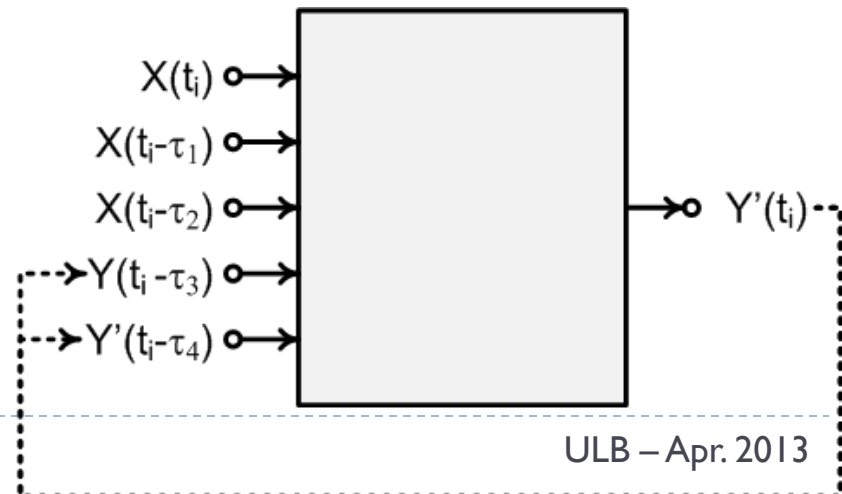
- ▶ Training of recurrent behavioural models is a problem
  - ▶ You can sample the output of the target system
  - ▶ *But you can not sample the output of a non-existent model...*
  - ▶ Risk that small modelling errors get amplified

# Training of Recurrent Models

- ▶ Series-parallel configuration (open-loop) :  
*Use training data points as recurrent input*



- ▶ Compensate the best you can by tuning the regression parameters on the model evaluated in closed-loop configuration





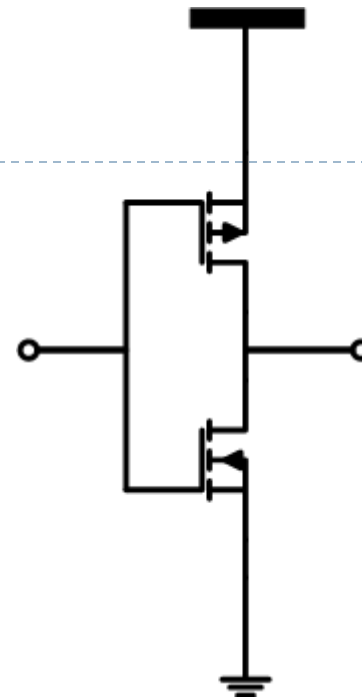
# Stability of the models with feedbacks

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- ▶ The stability analysis of recurrent neural networks is mostly based on simplification of the problem, e.g.
  - ▶ Lyapunov's indirect and direct methods in (Cao, 2006)
  - ▶ By employing a new Lyapunov–Krasovskii functional, a linear matrix inequality (LMI) approach is developed to establish sufficient conditions for the RNNs to be globally exponentially stable in (Liu, 2006).
- ▶ Stability analysis does not include the numerical stability problems of the circuit simulator!

# CMOS Inverter Test-case

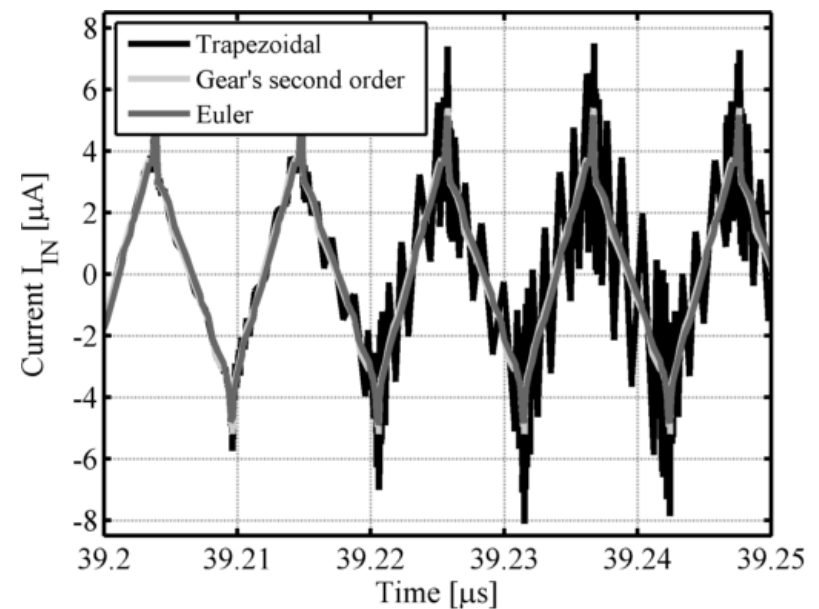
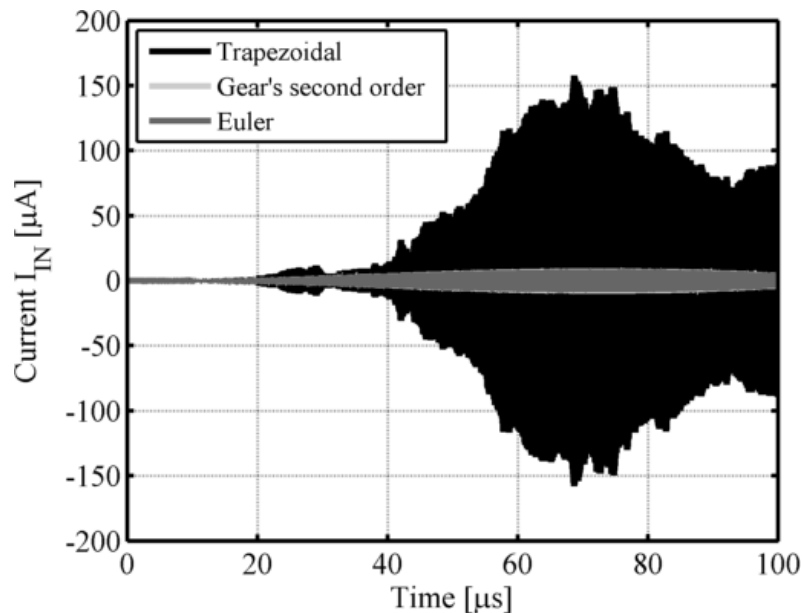
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- ▶ Basic building block of all logic circuits
- ▶ Consists mainly of two transistors
- ▶ Switching speed of the output depends on the load (usually capacitive)
- ▶ Driving strengths of the transistors depend on output voltage (drain voltage)
- ▶ Need to have output feedback in order to capture dynamic switching behaviour

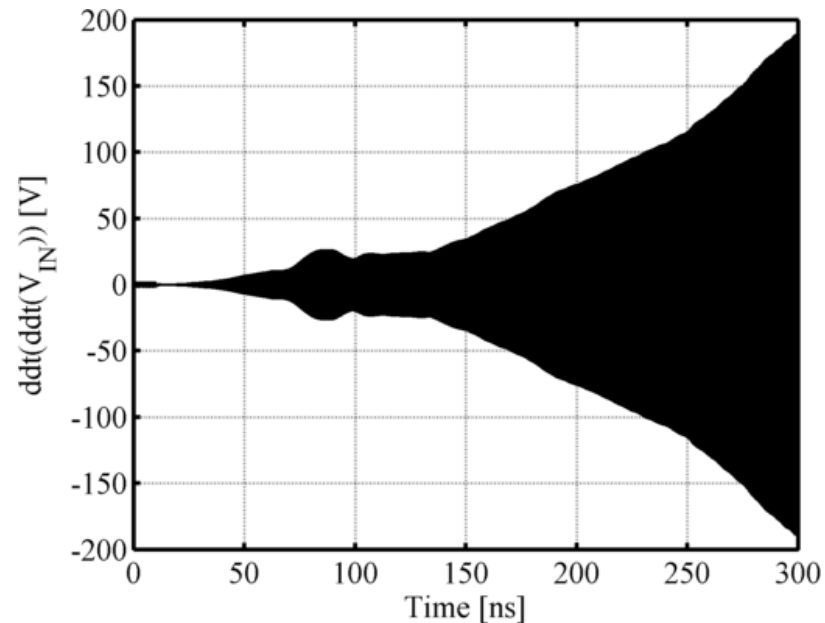
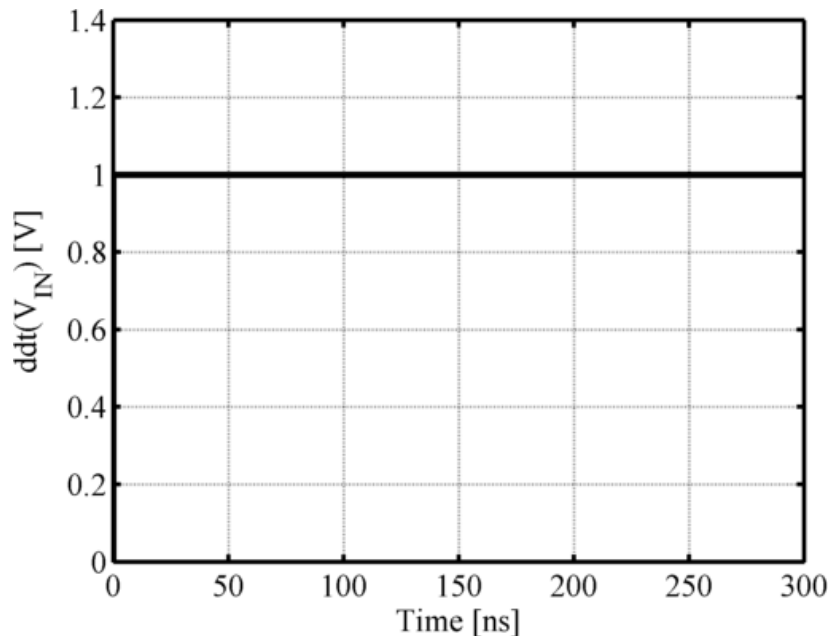
# CMOS inverter: Model does not work !

- ▶ Results in function of selected integration method
  - ▶ Model works fine in MATLAB / PYTHON, not in SPECTRE...
  - ▶ Applying a chirp signal on the gate
  - ▶ Looking at the gate charging current :



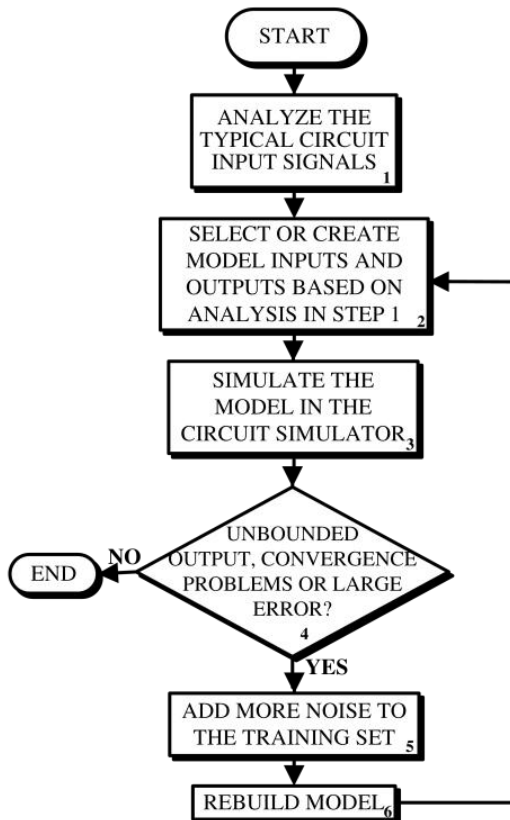
# Derivatives are generally problematic

- ▶ Derivatives calculated by SPECTRE for a linear ramp :



# Algorithmic Solution to the Problem

## ► Add white noise to the data-set...




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**Algorithm 1:** Method for checking and improving stability of black-box models (CISB)

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Step 1: The typical circuit inputs are analyzed in order to create sample cases of normal operation of the circuit.

Step 2: Model inputs and outputs are selected or created based on the analysis done in Step 1.

Step 3: Simulate the model in the circuit simulator.

Step 4: If the output is unbounded, convergence problems occur or the model output significantly deviates from the expected behaviour then go to Step 5, otherwise go to Step 2.

Step 5: Add more noise to the training data set.

Step 6: Rebuild the model and go to Step 2.

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# Algorithmic Solution to the Problem

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- ▶ Adding noise in each iteration. We are trying to find minimum noise level to suppress the circuit numerical problems.
- ▶ Number of SPICE evaluations should be as small as possible because they are computationally expensive.
- ▶ Minimum number of iterations according to the binary search algorithm
- ▶ A binary search halves the number of items to check with each iteration, so locating optimal noise level takes logarithmic time.
- ▶ Average number of SPICE evaluations is  $\log_2(N)-1$  where  $N$  is a number of possible levels that can be tested, e.g. for SNR from 0 to 100 dB with resolution of 0.5, average number of evaluations is only 6.6!
- ▶ If no upper (or lower) limit is defined, average number of evaluations is  $2*\log_2(k)+1$  where  $k$  is the (unknown) minimum noise level.





# Verilog-A Model (CMOS inverter)

```
// Example of a simple model of inverter built by TASVR algorithm.
// The number of SV is limited to 10 SVs (that is the reason why the behavioural description is small).
// INITIALISATION
#include "discipline.h
#include "constants.h

// In this simple example, inputs are input voltage (in1E) and delayed input voltage (in2E).
// The output is the output voltage.
// The delayed version can in2E can be generated inside of Verilog A code by absdelay command.

module Vout_inverter_tran( in1E, in2E, outE, gnd );

electrical in1E, in2E, outE, gnd;

real o1; real i1; real i2;

analog begin

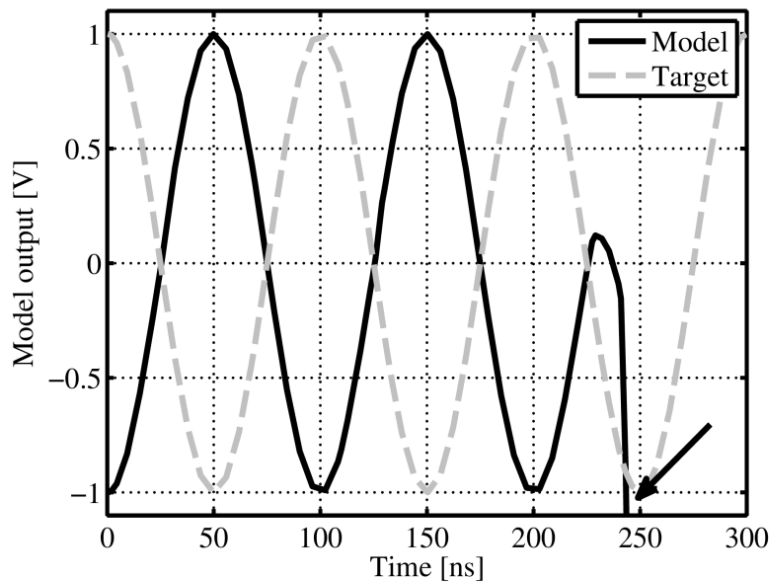
    // We first must scale inputs. In this case we scale to [-1,1] range.
    i1=(((1)-(-1))*(V(in1E, gnd)-(
        0)))/((
        3.3)-(
        0)) + (-1);
    i2=(((1)-(-1))*(V(in2E, gnd)-(-16140891.7306778)))/((15596982.6714803)-(-16140891.7306778)) + (-1);

    // module behavioral description. It is generated by TASVR algorithm and limited to 10SV.
    o1 = (2/(1+exp(-2*((2/(1+exp(-2*(i1*(-1.98355288e+00) + i2*(4.87907886e-01) + (1.24497687e+00)))))-1)*(1.48062767e+00) + (2/
(1+exp(-2*(i1*(5.91734491e+00) + i2*(5.96737824e+00) + (2.95055755e-01)))))-1)*(-4.02777537e-01) + (2/(1+exp(-2*(i1*
(2.79975258e+00) + i2*(-7.10623655e+00) + (2.78072909e+00)))))-1)*(-9.60205344e-02) + (2/(1+exp(-2*(i1*(1.40332998e+01) + i2*
(2.71512546e+00) + (8.63017720e-01)))))-1)*(-6.99170641e-01) + (2/(1+exp(-2*(i1*(4.02501497e+00) + i2*(-4.26195915e-
01) + (2.64414994e+00)))))-1)*(-1.33922945e+00) + (-1.81352214e-03))))-1);

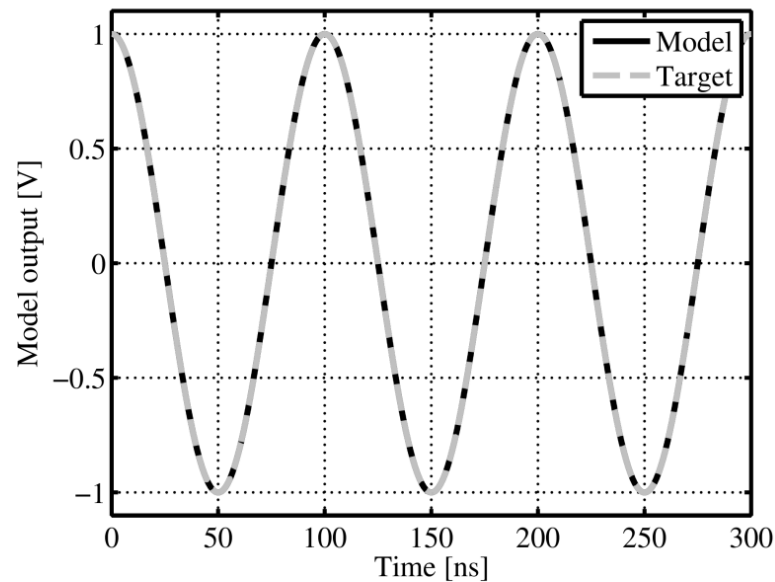
    // At last, we set the output voltage. Notice rescaling before applying voltage to the output of the model!
    V(outE,gnd) <+ ((o1-(-0000000000000000000001))*(3.2890231145676498414331945e+00)-(-2.6617793710389699157747856e-03)))/
((0000000000000000000001)-(-0000000000000000000001))+(-2.6617793710389699157747856e-03);

endmodule
```

# CMOS inverter model with CISB



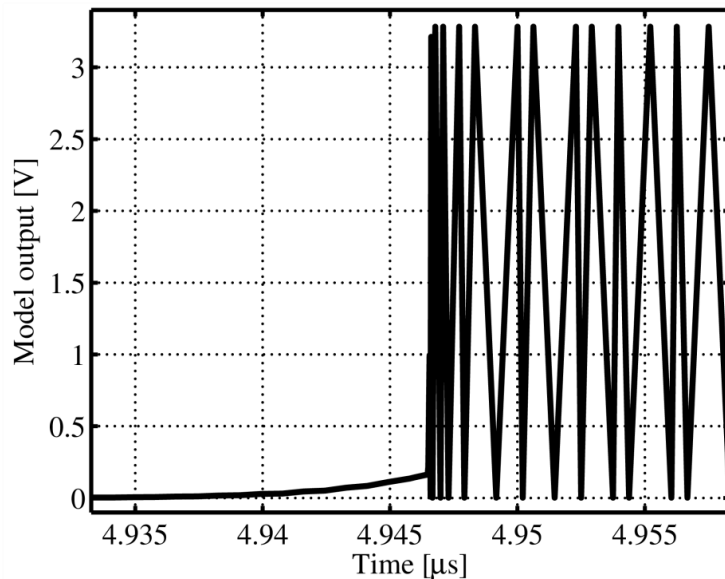
(a)



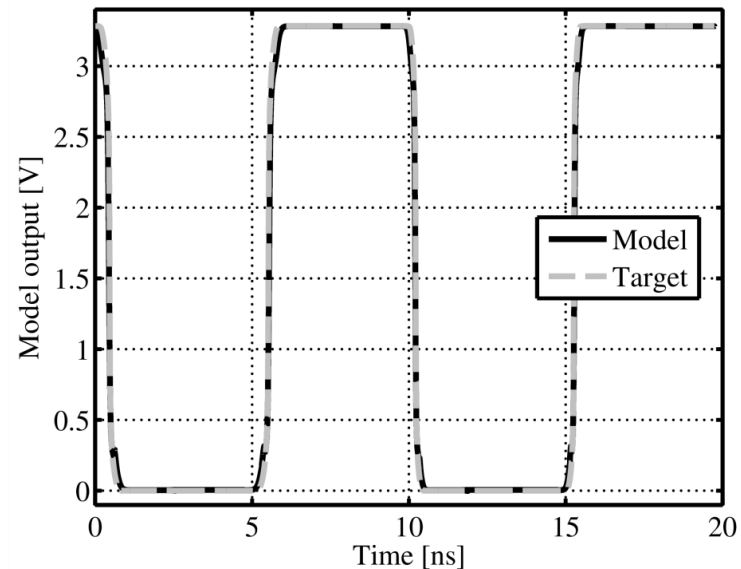
(b)

- ▶ (a) before and (b) after application of the CISB method
  - ▶ Signal to noise (SNR) ratio of the added white Gaussian noise to the feedback signal is equal to 75 dB
  - ▶ NRMSE = 2.1E-5 (with CISB)

# CMOS inverter model with CISB



(a)

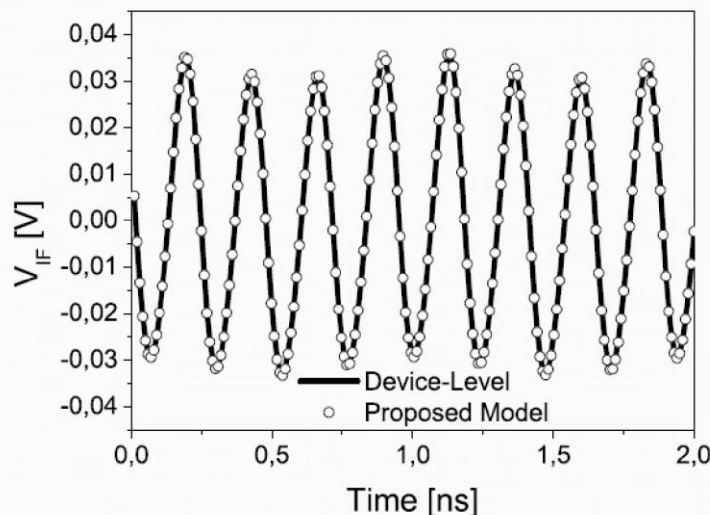
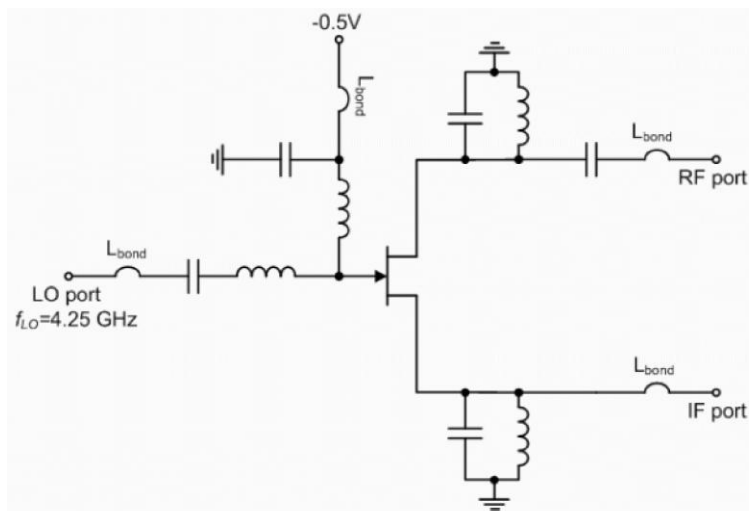


(b)

- ▶ (a) before and (b) after application of the CISB method
  - ▶ (a) zoomed in at the point where the simulator diverges
  - ▶ Signal to noise (SNR) ratio of the added white Gaussian noise to the feedback signal is equal to 50 dB.
  - ▶ NRMSE = 0.048

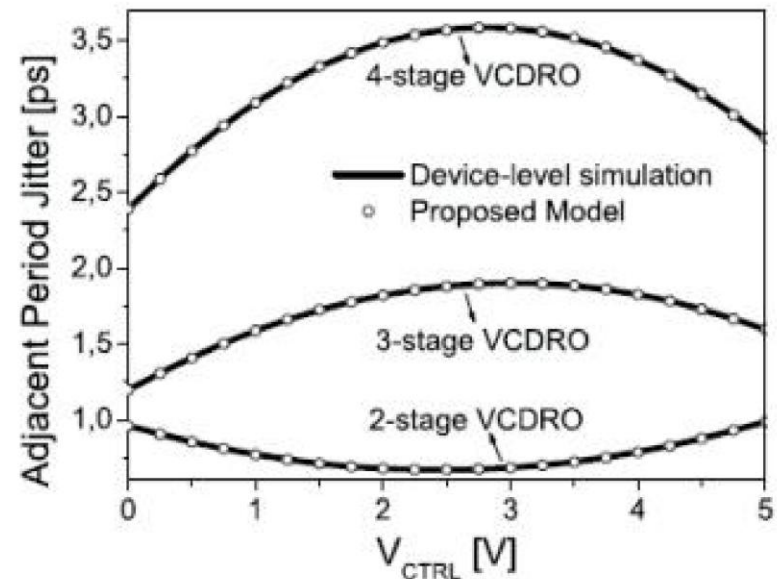
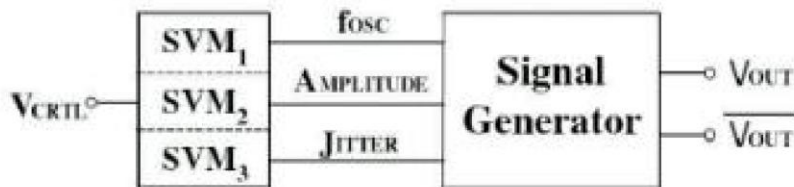
# Modelling of Resistive Mixer

- ▶ Training: - frequency  $f_{RF}$  is varied from 5.1 GHz to 5.3 GHz (50 MHz step) - power of  $V_{RF}$  is varied from -30 dBm to -40 dBm (step 2 dBm) - IF port is loaded with 45, 50 and 55 Ohm resistor
- ▶ Testing: - frequency  $f_{RF}$  is 5.225 GHz - power of  $V_{RF}$  is set to -35 dBm - IF port loaded with 52.5 Ohm- Not used in training set!



# Modelling of VCO

- ▶ GaAs 0.5 um SCFL Voltage Controlled Differential Oscillator
- ▶ Using signal generator as the output stage
  - ▶ Only 10 to 20 input-output pairs needed!





# Conclusions (modelling tips)

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- ▶ Mix generic stimuli (e.g. chirp waveform) with typical stimuli for the target electronic circuit to obtain training data set.
- ▶ Scale the data before applying machine learning techniques.
- ▶ Use delays to capture dynamic behaviour rather than derivatives, as it will result in much more stable model code
- ▶ Use feature/training data point selection methods.
- ▶ Don't use ANNs, they are prone to overfitting.
- ▶ If possible, simplify the modelling problem!  
Example: VCO signal generator.
- ▶ Always test in the circuit simulator.  
Adding white noise can improve stability.



# References

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- ▶ Barford, Lee A. et al. (Feb. 2005). "Method and apparatus for extraction of nonlinear black-box behavioral models from embeddings of the time-domain measurements". Patent US 6,850,871 (US).
  - ▶ Cao, Yi, Runtao Ding, and Q. J. Zhang (2006). "State-space dynamic neural network technique for high-speed IC applications: modeling and stability analysis". In: IEEE Transactions on Microwave Theory and Techniques 54.6, pp. 2398–2409.
  - ▶ Ceperic, V. and A. Baric (2004a). "Modeling of analog circuits by using support vector regression machines". In: Proceedings of the 11th IEEE International Conference on Electronics, Circuits and Systems, ICECS 2004, pp. 391–394.
  - ▶ — (May 2004b). "Modelling of SCFL circuits". In: Proceedings of the 27th International Convention MIPRO 2004: conferences Microelectronics, Electronics and Electronics Technologies (MEET) and Hypermedia and Grid System (HGS), pp. 72–77.
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# References

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- ▶ Feo, O. De and M. Storace (2005). "PWL approximation of nonlinear dynamical systems, part II: identification issues". In: *Journal of Physics: Conference Series* 22, pp. 30–42. Guo, Yunchuan et al. (2007).
  - ▶ Guo, Yunchuan et al. (2007). "A Support Vector Regression Nonlinear Model for SiC MESFET". In: *Proceeding of 2007 International Workshop on Electron Devices and Semiconductor Technology, EDST 2007*, pp. 153–156.
  - ▶ Guyon I., et al. (2006). "Feature Extraction: Foundations and Applications (Studies in Fuzziness and Soft Computing)". Springer-Verlag New York, Inc., Secaucus, NJ, USA.
  - ▶ Jaeger, H. The "echo state" approach to analysing and training recurrent neural networks. Tech. rep. 148. GMD – German National Research Institute for Computer Science.
  - ▶ — (2002). Tutorial on training recurrent neural networks, covering BPPT, RTRL, EKF and the "echo state network" approach. GMD Report. St. Augustin-Germany: Fraunhofer Institute AIS.
  - ▶ Karsmakers, P. et al. (2008). "Least Squares Support Vector Machines for Modelling Electronic Devices". In: *European Conference on the Use of Modern Information and Communication Technologies (ECUMICT)*. Ghent, Belgium, pp. 1–4.
  - ▶ Litovski, V. B. et al. (1992). "MOS Transistor Modeling Using Neural Network". In: *Electronics Letters* 28.18, pp. 1766–1768.
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# References

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- ▶ Litovski, V. B. et al. (2004). "ANN application to modelling of the D/A and A/D interface for mixed-mode behavioural simulation". In: *Journal of Circuits, Systems and Computers* 13.1, pp. 181–192.
- ▶ Liu Yurong, Zidong Wang, Xiaohui Liu (2006), Global exponential stability of generalized recurrent neural networks with discrete and distributed delays, *Neural Networks*, Volume 19, Issue 5, June 2006, Pages 667-675, ISSN 0893-6080, 10.1016/j.neunet.2005.03.015.
- ▶ Moriyasu, Hiro (Sept. 1994). "Behavioral model parameter extractor". Patent US 5,349,539 (US).
- ▶ Patan K. and M. Patan. (2010). "Selection of Training Data for Locally Recurrent Neural Network". In: *Artificial Neural Networks – ICANN 2010*. Ed. by K. Diamantaras, W. Duch, and L. S. Iliadis. Vol. 6353. *Lecture Notes in Computer Science*. Springer Berlin Heidelberg, pp. 134–137.
- ▶ Rutenbar, R. A., G. G. E. Gielen, and J. Roychowdhury (2007). "Hierarchical modeling, optimization, and synthesis for system-level analog and RF designs". In: *Proceedings of the IEEE* 95.3, pp. 640–669.
- ▶ Russell, J., P. Norvig (2009). *Artificial Intelligence: A Modern Approach*. Pearson Education.
- ▶ Schetzen, M. (1980). *The Volterra and Wiener Theories Nonlinear Systems*. New York: Wiley.
- ▶ Sevic, John F. and Gary R. Simpson (June 2006). "Method and apparatus for model extraction". Patent application 20060116857 (US).





# References

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- ▶ Settles, B. (2009). “Active Learning Literature Survey”. In: Computer Sciences Technical Report 1648. University of Wisconsin–Madison.
  - ▶ Taher, H., D. Schreurs, and B. Nauwelaers (2008). ” Black box modelling of the Op-Amp including switching power supply on effect”. In: AEU - International Journal of Electronics and Communications 62.7, pp. 544–548.
  - ▶ Verspecht, J. (2005). ”Large-signal network analysis”. In: IEEE Microwave Magazine 6.4, pp. 82–92.
  - ▶ Wang, J., P. Neskovic, and L. N. Cooper (2005). “Training data selection for support vector machines”. In: Proceedings of the First international conference on Advances in Natural Computation - Volume Part I. ICNC'05. Changsha, China: Springer-Verlag, 2005, pp. 554–564.
  - ▶ Wood, John and David E. Root (2005). Fundamentals of Nonlinear Behavioral Modelling for RF and Microwave Design. Artech House, Inc.
  - ▶ Zhang, Lei and Qi-Jun Zhang (2008). ”Neuro-space mapping technique for semiconductor device modeling”. In: Optimization and Engineering 9.4, pp. 393–405.
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